

Quarterly Reliability Monitoring Results

Quarters: Q1/2023 to Q4/2024

Based on structural similarity

Supplier		User Part Number				
Nexperia B.V.		PESD3USB30				
Name of Laboratory		Part Description		Protection INDI		
Assembly reliability labs		NXP ICN8 WLCSP package				
Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects
# 1	<b>TEST</b> Pre- and Post-Stress Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below
# 5	<b>HTRB</b> High Temperature Reverse Bias	MIL-STD-750-1 M1038 Method A Tj = Tjmax, Vr = 100% of max. datasheet reverse voltage	1000 hours	96	3840	0
# 7	<b>TC</b> Temperature Cycling	JESD22-A104 -40 °C to 125°C	1000 cycles	32	1280	0
# 8 or	<b>UHAST</b> Unbiased HAST	JESD22-A118 Tamb = 130 °C, RH = 85 %	96 hours	n.a.	n.a.	n.a.
# 8a	<b>AC</b> Autoclave	JESD22-A102 Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)				
# 9	<b>HAST</b> Highly Accelerated Stress Test	JESD22-A110 Tamb = 130 °C, RH = 85%, VR = 80 % of rated reverse voltage <sup>[1]</sup>	96 hours	32	1280	0
# 10	<b>IOL</b> Intermittent Operating Life	MIL-STD-750 Method 1037 ton = toff, devices powered to insure ΔTj = 100 °C for 15000 cycles	1000 hours	n.a.	n.a.	n.a.
# 20	<b>RSH</b> Resistance to Solder Heat	JESD22-A111 260 °C ± 5 °C	10 s	n.a.	n.a.	n.a.
# 21	<b>SD</b> Solderability	J-STD-002		n.a.	n.a.	n.a.

[1]The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5)  
Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
NXP ICN8	Protection INDI	3840	0	1,1	9,04E+08